

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10656846	CHU ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	SIMON KE	2174

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
715	780, 781	1/22/08	PK
715	780, 781	7/6/08	PK
715	780, 781, 501, 513, 84-843, 790, 797, 853-855 and 760	1/4/09	PK
715	780, 781, 501, 513, 84-843, 790, 797, 853-855 and 760	7/17/09	PK
715	780, 781, 501, 513, 84-843, 790, 797, 853-855 and 760	12/14/09	PK

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
East Text Search (715/501, 513, 84-843, 790, 797, 781, 853-855 and 760 USPAT; USPUB; EPO; JPO; DERWENT)	1/22/08	PK
East Text Search (715/501, 513, 84-843, 790, 797, 781, 853-855 and 760 USPAT; USPUB; EPO; JPO; DERWENT)	7/6/08	PK
East Text Search (715/501, 513, 84-843, 790, 797, 781, 853-855 and 760 USPAT; USPUB; EPO; JPO; DERWENT)	1/4/09	PK
East Text Search (715/501, 513, 84-843, 790, 797, 781, 853-855 and 760 USPAT; USPUB; EPO; JPO; DERWENT)	7/17/09	PK
East Text Search (715/501, 513, 84-843, 790, 797, 781, 853-855 and 760 USPAT; USPUB; EPO; JPO; DERWENT)	12/14/09	PK

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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